


## FCC TEST REPORT

**Product** : Clean Wipe Keyboard  
**Trade mark** :   
**Model/Type reference** : SSKSV099  
**Serial Number** : N/A  
**Ratings** : DC 5V  
**FCC ID** : X7LSSKSV099  
**Report Number** : EESZF11140005  
**Date** : Dec. 30, 2013  
**Regulations** : See below

Test Standards	Results
<input checked="" type="checkbox"/> 47 CFR FCC Part 15 Subpart B: 2012	PASS

Prepared for:  
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Date: Dec. 30, 2013



Check No.: 1702082273

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*(Note: N/A means not applicable)*

## 1. GENERAL INFORMATION

**Applicant:** Seal Shield Corporation  
3105 Riverside Avenue Jacksonville, FL 32205


**Manufacturer:** CAN Technology Co., Ltd.  
No. 827 Sec. 1St , Chung Hua Rd. Chung Li city Taoyuan  
Hsien Taiwan

**Factory:** SQT shenzhen SQT Electronics Co., Ltd.  
Bldg B4, Hengji Industry Zone, He Yi Village, Sha Jing Town,  
Bao An Area, Shenzhen, Guangdong Province, China

**Equipment Authorization:** Certification

**FCC ID:** X7LSSKSV099

**Product:** Clean Wipe Keyboard

**Trade mark:** 

**Model/Type reference:** SSKSV099

**Serial Number:** N/A

**Report Number:** EESZF11140005

**Sample Received Date:** Nov. 15, 2013

**Sample tested Date:** Nov. 15, 2013 to Dec. 29, 2013

## 2. TEST SUMMARY

The Product has been tested according to the following specifications:

Standard	Test Item	Test
FCC 15.107	Conducted Emission	Yes
FCC 15.109	Radiated Emission	Yes

## 3. MEASUREMENT UNCERTAINTY

Where relevant, the following measurement uncertainty levels have been estimated for tests performed on the Product as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

Test item	Value (dB)
Conducted disturbance	3.0
Radiated disturbance (30MHz to 1GHz)	4.9

## 4. PRODUCT INFORMATION AND TEST SETUP

### 4.1. PRODUCT INFORMATION

**Ratings:** DC 5V

### 4.2. TEST SETUP CONFIGURATION

See test photographs attached in Appendix 1 for the actual connections between Product and support equipment.

### 4.3. SUPPORT EQUIPMENT

No.	Device Type	Brand	Model	Series No.	Data Cable	Remark
1.	Notebook	DELL	Vostro 3400	GYQTVP1	N/A	FCC DOC
2.	Mouse	L.Selectron	M004	02284699	Un-shielded 1.2M	FCC DOC

Notes:

1. All the equipment/cables were placed in the worst-case configuration to maximize the emission during the test.
2. Grounding was established in accordance with the manufacturer's requirements and conditions for the intended use.

## 5. FACILITIES AND ACCREDITATIONS

### 5.1 TEST FACILITY

All test facilities used to collect the test data are located at Hongwei Industrial Zone, 70 Area, Bao'an District, Shenzhen, Guangdong, China. The site and apparatus are constructed in conformance with the requirements of ANSI C63.4, CISPR 16-1-1 and other equivalent standards.

### 5.2 TEST EQUIPMENT LIST

**Instrumentation:** The following list contains equipments used at CTI for testing.

The calibrations of the measuring instruments, including any accessories that may effect such calibration, are checked frequently to assure their accuracy. Adjustments are made and correction factors applied in accordance with instructions contained in the manual for the measuring instrument.

**Equipment used during the tests:**

Shielding Room No. 1 - Conducted Emission Test				
Equipment	Manufacturer	Model	Serial No.	Due Date
Receiver	R&S	ESCI	100009	07/19/2014
LISN	R&S	ENV216	100098	07/19/2014

3M Semi-anechoic Chamber (1)- Radiated disturbance Test				
Equipment	Manufacturer	Model	Serial No.	Due Date
3M Chamber & Accessory Equipment	ETS-LINDGREN	FACT-3	3510	07/12/2016
Spectrum Analyzer	Agilent	E4443A	MY45300910	01/18/2014
Receiver	R&S	ESCI	100435	07/19/2014
TRILOG Broadband Antenna	schwarzbeck	VULB 9163	618	06/25/2014
Multi device Controller	ETS-LINGREN	2090	00057230	N/A

## 6. SYSTEM TEST CONFIGURATION

### 6.1. JUSTIFICATION

The system was configured for testing in a typical fashion (as a customer would normally use it), The Product was placed on a turn table, which enabled the engineer to maximize emissions through its placement as outlined in ANSI C63.4 (2009).

The Product was powered by DC 5V during test.

For maximizing emissions, the Product was rotated through 360°, the antenna height was varied from 1 meter to 4 meters above the ground plane, and the antenna polarization was changed. The rear of unit shall be flushed with the rear of the table.

All readings are extrapolated back to the equivalent three meter reading using inverse scaling with distance. Analyzer resolution is 100 kHz or greater for frequencies below 1000 MHz. The spurious emissions more than 20 dB below the permissible value are not reported.

### 6.2. PRODUCT EXERCISING SOFTWARE

No Software was used during testing.

## 7. CONDUCTED EMISSION TEST

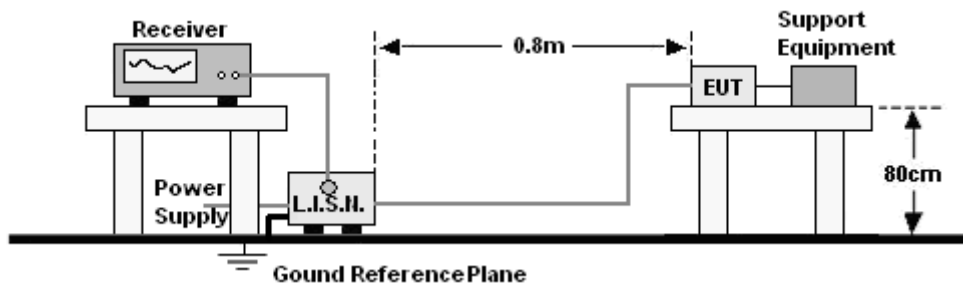
### 7.1. LIMITS

Limits for Class B digital devices

Frequency range (MHz)	Limits dB(μV)	
	Quasi-peak	Average
0,15 to 0,50	66 to 56	56 to 46
0,50 to 5	56	46
5 to 30	60	50

**NOTE:** 1. The lower limit shall apply at the transition frequencies.  
2. The limit decreases linearly with the logarithm of the frequency in the range 0.15 to 0.50 MHz.

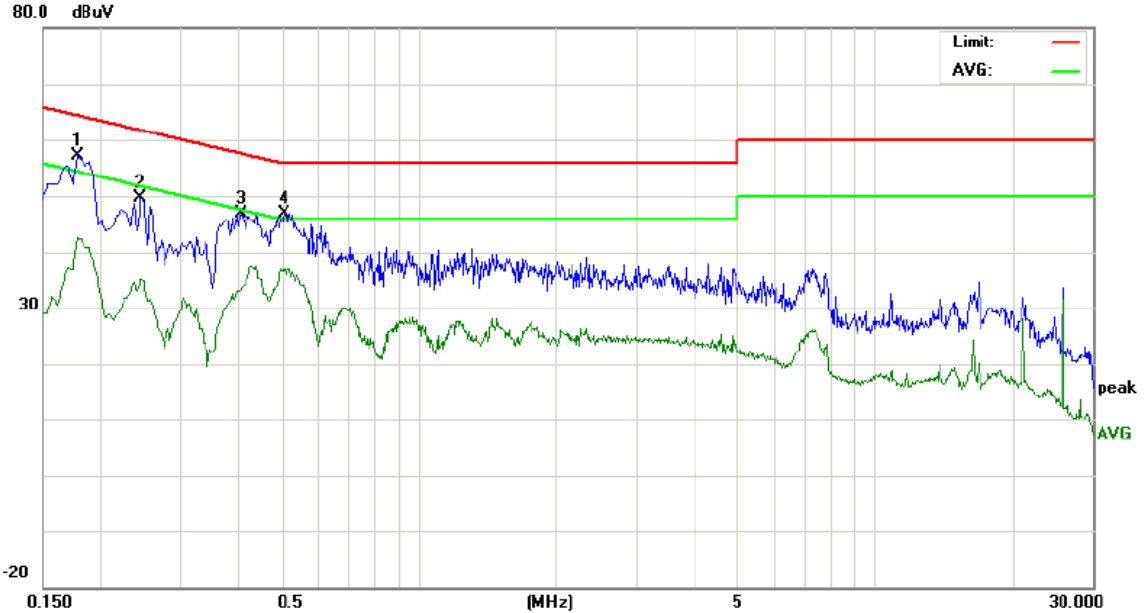
### 7.2. BLOCK DIAGRAM OF TEST SETUP



### 7.3. PROCEDURE OF CONDUCTED EMISSION TEST

- The Product was placed on a nonconductive table above the horizontal ground reference plane, and 0.4 m from the vertical ground reference plane, and connected to the main through Line Impedance Stability Network (L.I.S.N).
- The RBW of the receiver was set at 9 kHz in 150 kHz ~ 30MHz with Peak and AVG detector in Max Hold mode. Run the receiver's pre-scan to record the maximum disturbance generated from Product in all power lines in the full band.
- For each frequency whose maximum record was higher or close to limit, measure its QP and AVG values and record.

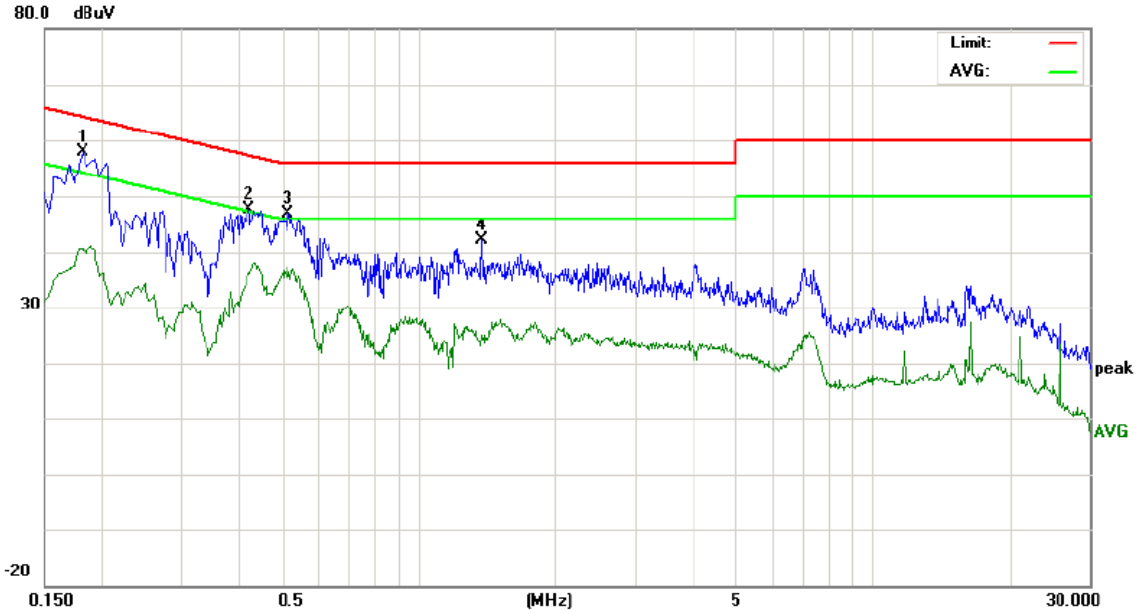
**7.4. WORST CASE TEST GRAPHS AND TEST DATA**



Site site #1  
 Limit: FCC Class B CE (QP)  
 EUT: Clean Wipe Keyboard  
 M/N: SSKSV099  
 Mode: Normal  
 Note:

Phase: L1  
 Power: AC 120V/60Hz  
 Temperature: 18  
 Humidity: 45 %

No.	Freq. MHz	Reading_Level (dBuV)			Correct Factor dB	Measurement (dBuV)			Limit (dBuV)		Margin (dB)		P/F	Comment
		Peak	QP	AVG		peak	QP	AVG	QP	AVG	QP	AVG		
1	0.1780	47.32	42.80	29.52	9.78	57.10	52.58	39.30	64.57	54.57	-11.99	-15.27	P	
2	0.2460	39.86	35.06	24.05	9.80	49.66	44.86	33.85	61.89	51.89	-17.03	-18.04	P	
3	0.4100	37.11	32.48	23.01	9.80	46.91	42.28	32.81	57.65	47.65	-15.37	-14.84	P	
4	0.5100	37.14	33.32	26.77	9.80	46.94	43.12	36.57	56.00	46.00	-12.88	-9.43	P	



Site site #1  
 Limit: FCC Class B CE (QP)  
 EUT: Clean Wipe Keyboard  
 M/N: SSKSV099  
 Mode: Normal  
 Note:

Phase: **N**  
 Power: AC 120V/60Hz

Temperature: 18  
 Humidity: 45 %

No.	Freq. MHz	Reading_Level (dBuV)			Correct Factor dB	Measurement (dBuV)			Limit (dBuV)		Margin (dB)		P/F	Comment
		Peak	QP	AVG		peak	QP	AVG	QP	AVG	QP	AVG		
1	0.1819	48.19	41.58	29.79	9.78	57.97	51.36	39.57	64.39	54.39	-13.03	-14.82	P	
2	0.4220	37.78	32.76	26.08	9.80	47.58	42.56	35.88	57.41	47.41	-14.85	-11.53	P	
3	0.5180	37.06	33.71	26.89	9.80	46.86	43.51	36.69	56.00	46.00	-12.49	-9.31	P	
4	1.3779	32.40	22.85	14.10	9.84	42.24	32.69	23.94	56.00	46.00	-23.31	-22.06	P	



## 8. RADIATED EMISSION TEST

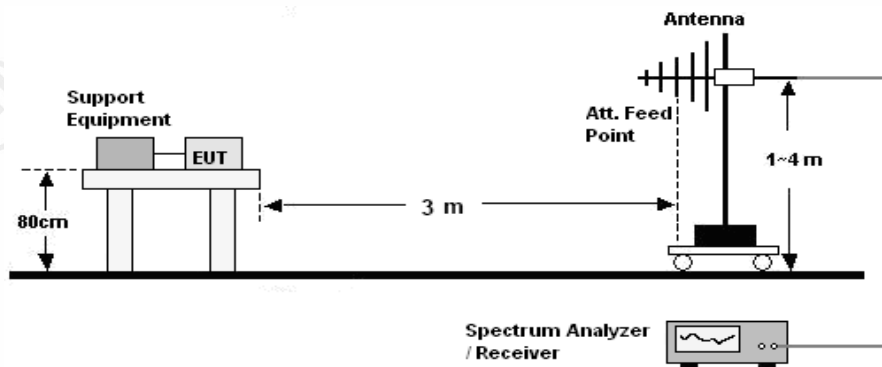
### 8.1. LIMITS

Limits for Class B digital devices

Frequency (MHz)	limits at 3m dB(μV/m)
30-88	40.0
88-216	43.5
216-960	46.0
Above 960	54.0

- NOTE:**
1. The lower limit shall apply at the transition frequency.
  2. The limits shown above are based on measuring equipment employing a CISPR quasi-peak detector function for frequencies below or equal to 1000MHz.
  3. The limits shown above are based on measuring equipment employing an average detector function for frequencies above 1000MHz.

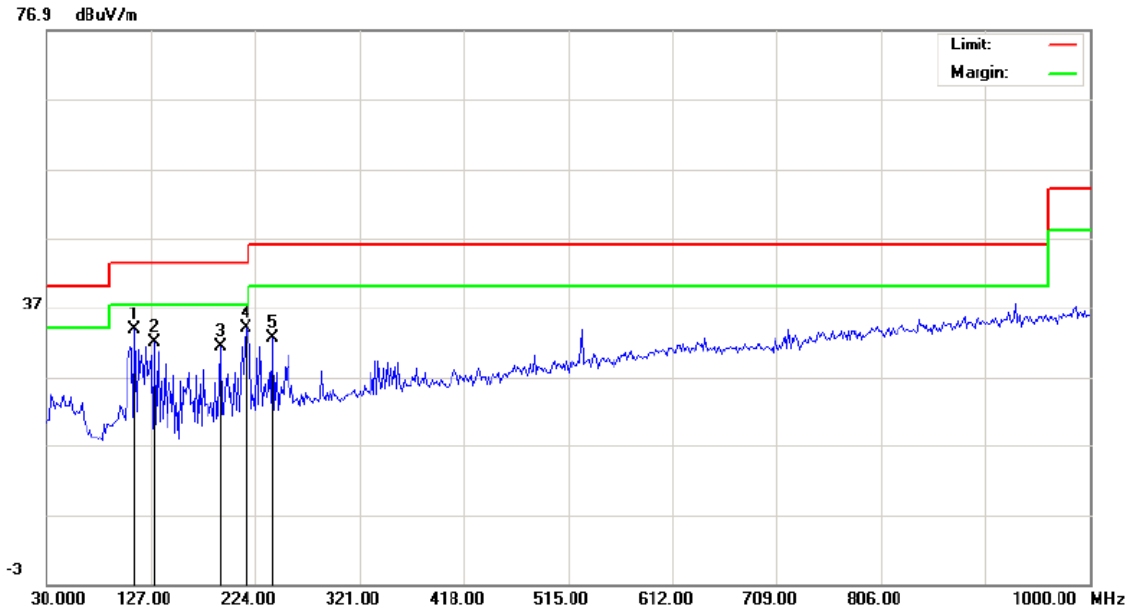
### 8.2. BLOCK DIAGRAM OF TEST SETUP



### 8.3. PROCEDURE OF RADIATED EMISSION TEST

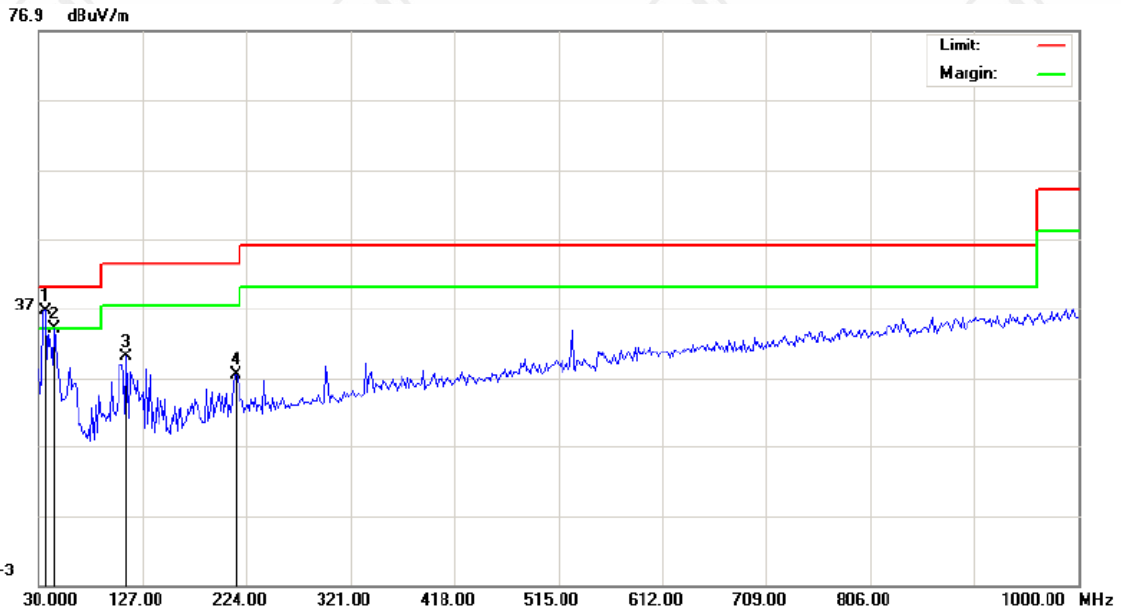
- a. The Product was placed on the non-conductive turntable 0.8m above the ground at a chamber.
- b. Set the spectrum analyzer/receiver in Peak detector, Max Hold mode, and 100 kHz RBW. Record the maximum field strength of all the pre-scan process in the full band when the antenna is varied between 1~4 m in both horizontal and vertical, and the turntable is rotated from 0 to 360 degrees.
- c. For each frequency whose maximum record was higher or close to limit, measure its QP value (120 kHz RBW): vary the antenna's height and rotate the turntable from 0 to 360 degrees to find the height and degree where Product radiated the maximum emission, then set the test frequency analyzer/receiver to QP Detector and specified bandwidth with Maximum Hold Mode, and record the maximum value.

**8.4. WORST CASE TEST GRAPHS AND TEST DATA**



Site site #1 Polarization: **Horizontal** Temperature: 18  
 Limit: FCC PART15 B Power: DC 5V Humidity: 45 %  
 EUT: Clean Wipe Keyboard  
 M/N: SSKSV099  
 Mode: Normal  
 Note:

No.	Freq. MHz	Reading_Level (dBuV)			Correct Factor dB	Measurement (dBuV/m)			Limit (dBuV/m)		Margin (dB)		P/F	Comment
		Peak	QP	AVG		peak	QP	AVG	QP	AVG	QP	AVG		
1	112.4500	20.63			13.08	33.71			43.50		-9.79		P	
2	130.2332	20.12			11.90	32.02			43.50		-11.48		P	
3	191.6667	18.07			13.35	31.42			43.50		-12.08		P	
4	215.9167	19.73			14.25	33.98			43.50		-9.52		P	
5	240.1667	17.89			14.78	32.67			46.00		-13.33		P	



Site site #1 Polarization: **Vertical** Temperature: 18  
 Limit: FCC PART15 B Power: DC 5V Humidity: 45 %  
 EUT: Clean Wipe Keyboard  
 M/N: SSKSV099  
 Mode: Normal  
 Note:

No.	Freq. MHz	Reading_Level (dBuV)			Correct Factor dB	Measurement (dBuV/m)			Limit (dBuV/m)		Margin (dB)		P/F	Comment
		Peak	QP	AVG		peak	QP	AVG	QP	AVG	QP	AVG		
1	36.4667	22.74	20.36		13.93	36.67	34.29	40.00		-5.71		P		
2	44.5500	19.03			15.05	34.08		40.00		-5.92		P		
3	112.4500	16.85			13.08	29.93		43.50		-13.57		P		
4	214.3000	13.15			14.21	27.36		43.50		-16.14		P		

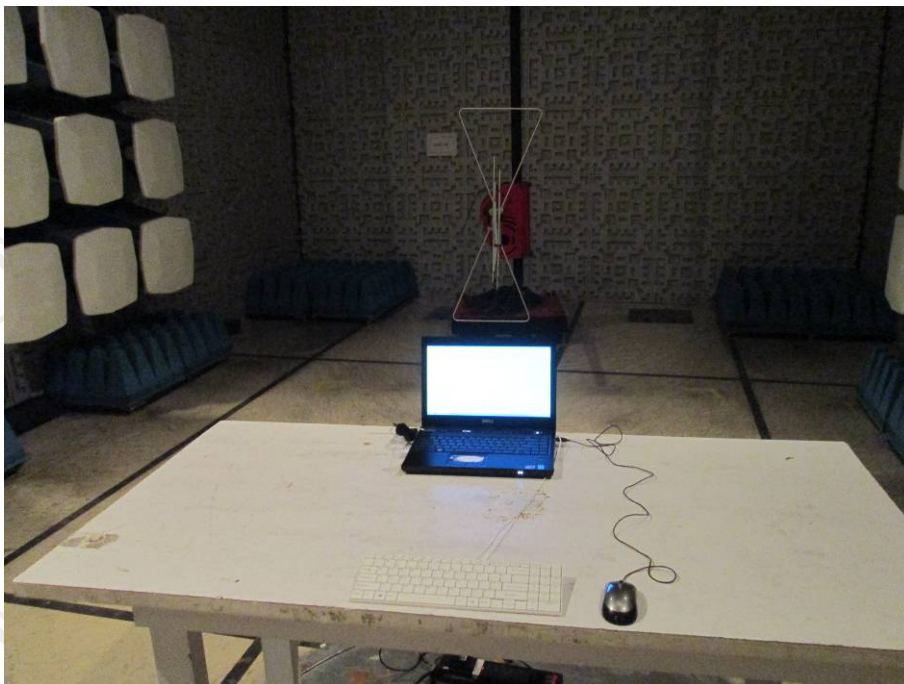
**Remark:**

The highest frequency of the internal sources of the EUT is less than 1MHz, so the measurement shall only be made up to 1 GHz.

## APPENDIX 1 PHOTOGRAPHS OF TEST SETUP



**CONDUCTED EMISSION TEST SETUP**



**RADIATED EMISSION TEST SETUP**

## APPENDIX 2 EXTERNAL PHOTOGRAPHS OF PRODUCT

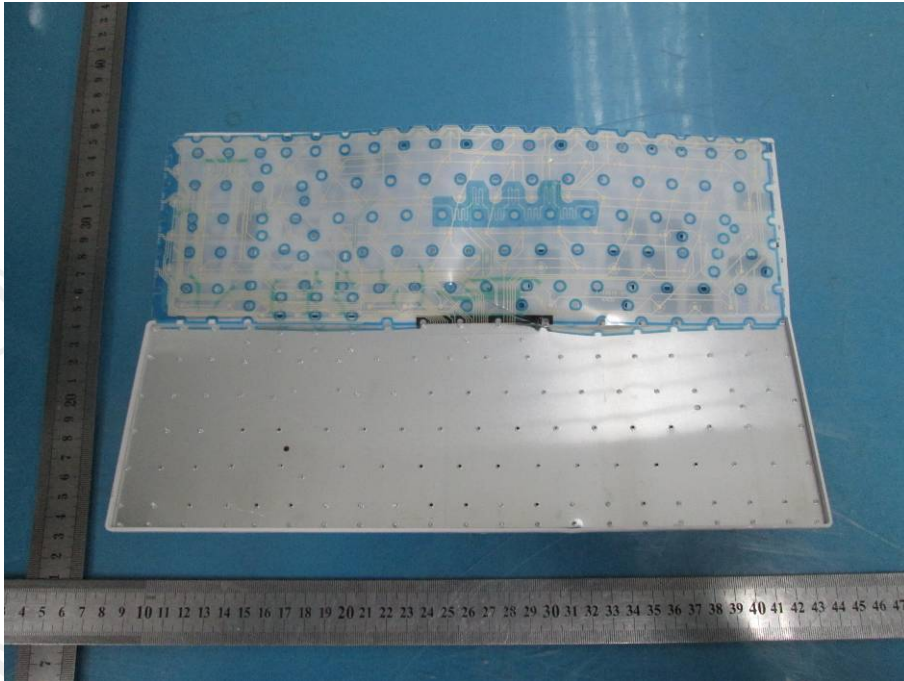


External View of Product-1

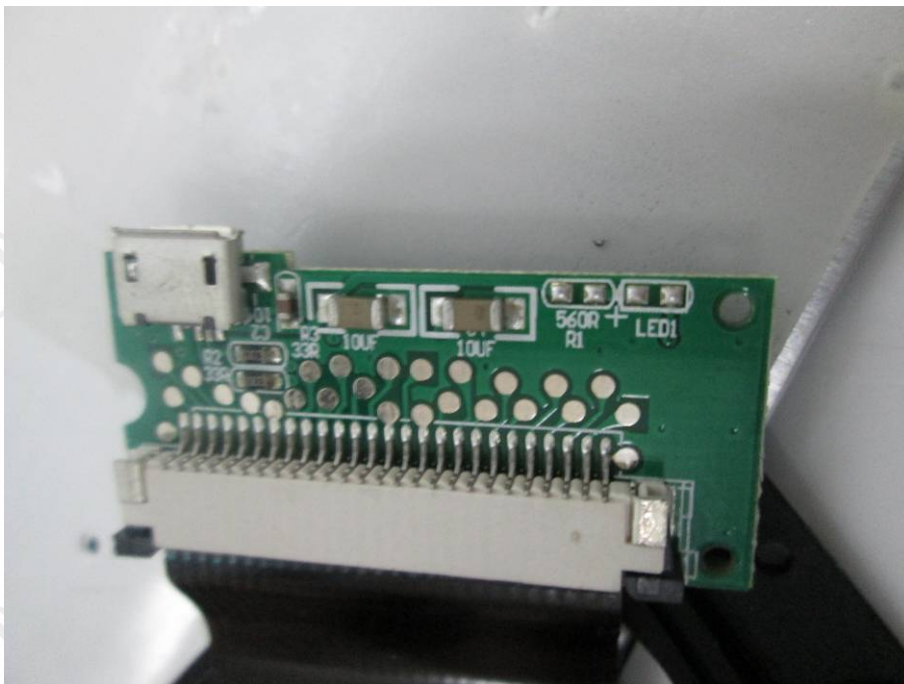


External View of Product-2

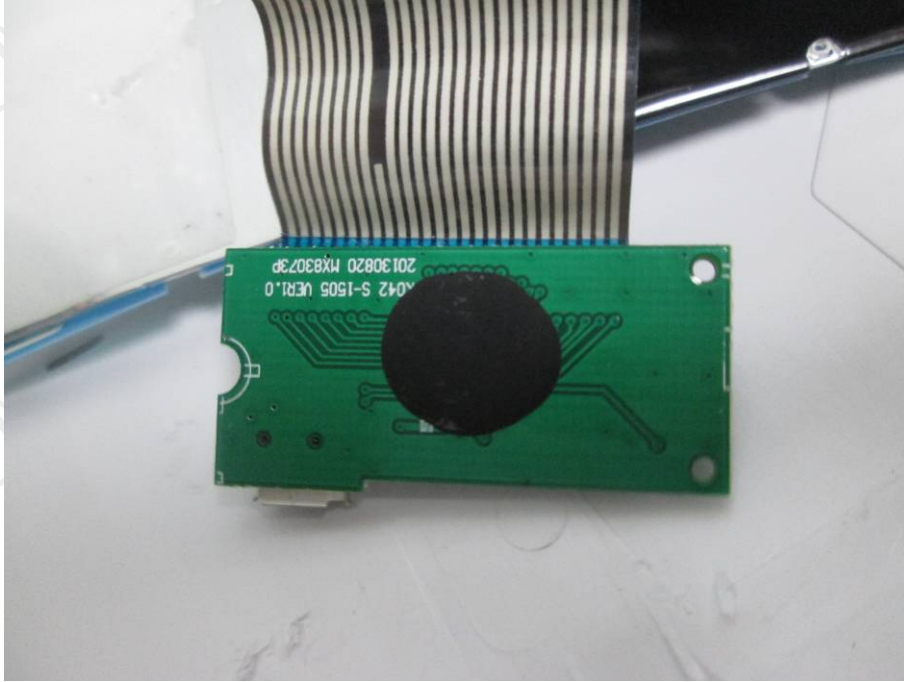
### APPENDIX 3 INTERNAL PHOTOGRAPHS OF PRODUCT



Internal View of Product-1



Internal View of Product-2



Internal View of Product-3

\*\*\* End of Report \*\*\*

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